## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10579418	STEK ET AL.
Examiner	Art Unit
Huynh, Phuong	2857

## **SEARCHED**

Class	Subclass	Date	Examiner
702	150	04/17/2007	PH
73	865.9	04/18/2007	PH
324	207.2; 207.25	04/18/2007	PH
UPDATED	ABOVE	08/10/07	PH
702	109-113, 116, 142-147,151-153, 163	08/10/2007	PH
324	76.12,76.14	08/10/2007	PH
UPDATED	ABOVE	08/12/2007	PH
341	8,115	08/12/2007	PH
324	207.12, 207.14; 76.13	08/12/2007	PH
UPDATED	ABOVE	11/19/2007	PH
702	94	11/21/2007	PH
UPDATED	ABOVE	03/11/2008	PH

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Search Notes	Date	Examiner
Consulted with Primary Examiner Blane Jackson (AU 2618): no search in 455	04/18/2007	PH
Consulted with Primary Examiner Thomas Noland : 73/865.9; 324/207.2,207.25	04/18/2007	PH
702/150; 73/865.9; 324/207.2, 207.25 with text	04/18/2007	PH
Assignment data (eDan)	04/18/2007	PH
702/109-113, 116, 142-147,150-153, 163; 324/207.2; 207.25,76.12,76.14; 73/865.9 with text	08/10/2007	PH
702/109-113, 116, 142-147,150-153, 163; 324/207.2; 207.12, 207.14, 207.25,76.12,76.13,76.14; 73/865.9; 341/8, 15 with text	8/12/2007	PH
Assignment data (eDan) updated	11/19/2007	PH
702/109-113, 116, 142-147,150-153, 163; 324/207.2; 207.12, 207.14, 207.25,76.12,76.13,76.14; 73/865.9; 341/8, 15 with text	11/19/2007	PH
702/94 with text	11/21/2007	PH
Assignment data (eDan)	03/11/2008	PH
Consulted with Primary Examiner Jeff West on allowance (OK) and updated search (no new classes/subclasses needed)	03/11/2008	PH
702/109-113, 116, 142-147,150-153, 163; 324/207.2; 207.12, 207.14, 207.25,76.12,76.13,76.14; 73/865.9; 341/8, 15 with text	03/11/2008	PH

## **INTERFERENCE SEARCH**

U.S. Patent and Trademark Office Part of Paper No.: 20080311

Class	Subclass	Date	Examiner
702	112,113,145	08/12/2007	PH
73	865.9	8/12/2007	PH
341	8,115	8/12/2007	PH
324	207.12; 76.13	8/12/2007	PH
UPDATED	ABOVE	11/19/2007	PH
702	94	11/21/2007	PH
UPDATED	ABOVE	03/11/2008	PH

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